General Description of Zeiss SEM Short Pin Stubs

The SEM pin stubs for the Zeiss and LEO SEMs, CrossBeams or SEM/FIB systems have a 6mm short pin. The pin diameter for all these pin stubs is 3.2mm (1/8'') diameter. In different styles and sizes. The SEM pin stubs are manufactured according to original specifications for the pin stubs, made from high quality, vacuum grade aluminum.

Standard flat SEM pin stubs platform height is 3.2mm and provide a groove for holding and handling. The following standard flat SEM pin stubs are available:

Flat Zeiss pin stubs

- 6.4mm stub diameter
- 9.5mm stub diameter
- 12.7mm stub diameter
- 25mm stub diameter
- 32mm stub diameter
- 38mm stub diameter
- 50mm stub diameter
- 63mm stub diameter
- 100mm stub diameter

Angled Zeiss pin stubs to quickly image a sample under 45° or 90° w/o tilting the sample stage:

- 12.7mm stub diameter with 45° and 45/90°
- 25mm diameter with 45°, 45/90°, double 45/90° and double 90°

Flat Zeiss pin stubs Ø12.7mm with 6mm extra height. Useful for marking, shorter working distance or to make your own custom stubs.

Low profile Ø12.7 pin stubs to enable very short working distances for high resolution SEM imaging and FIB operations

Engraved pin stubs with engraved patterns and numbering for mounting multiple samples or for relocating a sample. Stub diameters are 12.7, 19, 25.4 and 32mm